

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number PZU8.2B1A-Q Part Description											
									Nexperia DHAM Zener		'ener		
									SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects							
			TEST										
			Pre- and Post-Stress										
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below							
		JESD22-A113											
		Bake Tamb = 125 °C	24 hours										
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours			_							
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0							
		MIL-STD-750-1											
	HTRB	M1038 Method A											
" 54		Tj = Tjmax, VR = 80 % of rated reverse	10001	100	11000								
# B1	Bias	voltage	1000 hours	198	11960	0							
		MIL-STD-750-1											
	CCOR	M1038 Method B											
" D41	SSOP Steady State Operational	Tj = Tjmax, Iz = 100% of max. datasheet reverse current	10001	2.4	1760	•							
# B1b	Steady State Operational	reverse current	1000 hours	24	1760	0							
	тс	JESD22-A104											
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 evelee	240	14000	0							
# A4	remperature Cycling	-03 C to Tjillax, flot to exceed 130 C	1000 cycles	240	14800	0							
İ	UHAST	JESD22-A118											
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %											
, 713 31	Official Control	JESD22-A102	-96 hours	240	14800	0							
	AC	Tamb = 121 °C, RH = 100 %											
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)											
# AJ all	Addedave	11c33d1c = 203 ki d (23.7 p3id)											
	НЗТRВ	JESD22-A101											
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of											
# A2 alt		rated reverse voltage ^[1]	1000 hours	240	14800	0							
" NE dic		MIL-STD-750 Method 1037	1000 110010	2.0	1.000								
	IOL	ton = toff, devices powered to insure ΔT_j =											
# A5	Intermittent Operating Life		1000 hours	264	16720	0							
			_300	_0.	_0, _0	-							
	RSH	JESD22-A111											
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	184	5520	0							
	SD		_,,,	_0.	-520	-							
# C10	Solderability	J-STD-002		501	5010	0							

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11960	0	0,36	2,82E+09

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